



EEL3701: Digital Logic & Computer Systems

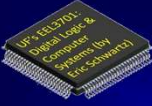
Menu

- IC Static Characteristics
 - > Rise-time, Fall-time, Ringing
 - > Propagation Delay
 - > Inertial Delay
 - > Fan-in, Fan-out
 - > Noise Margin
 - > Race Condition/Hazard



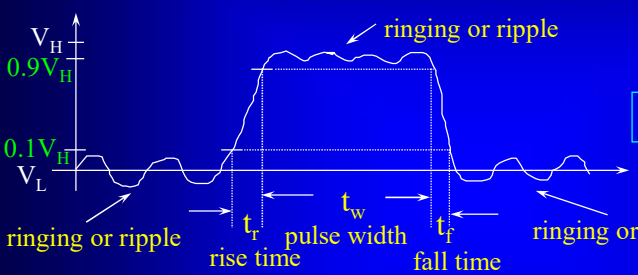
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Static Parameters of ICs



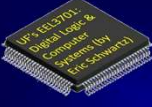
Typically $t_f < t_r$

Let $\Delta V = V_H - V_L$

- t_r : Rise time: amount of time for a signal to go from $V_L + (10\%)(\Delta V)$ to $V_L + (90\%)(\Delta V)$. If $V_L = 0$, then t_r is time of $10\%V_H$ to $90\%V_H$.
- t_f : Fall time: amount of time for a signal to go from $V_L + (90\%)(\Delta V)$ to $V_L + (10\%)(\Delta V)$. If $V_L = 0$, then t_r is time of $90\%V_H$ to $10\%V_H$.
- Ringing is undesirable

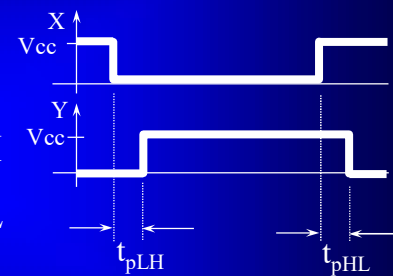
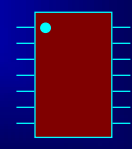
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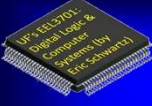
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Static Parameters of ICs:
Propagation/Transport Delay

t_{pLH} : propagation delay from L to H
 t_{pHL} : propagation delay from H to L
 Typically, $t_{pHL} > t_{pLH}$

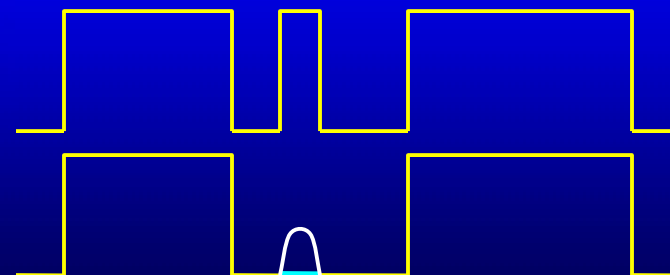
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Inertial Delay

- If a pulse is too narrow, it will be ignored
- This is the **inertial delay**
- Neglecting propagation delay:

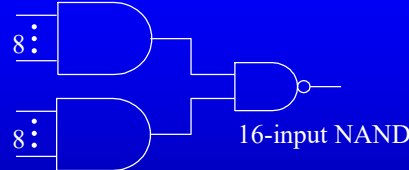
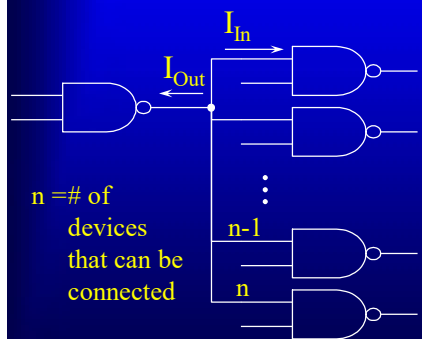


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Static Parameters of ICs: Fan-In, Fan-Out

- Fan-In: # of inputs
- Fan-Out: # of outputs that can be driven
- Fan-In limits the size of gates because the more the inputs, the slower the device.
- To make a 16 input NAND: →

$n = \#$ of devices that can be connected

- Fan-Out imposes limits on the # of devices that can be reliably driven by the gates.
- We define I_{Out} & I_{In} as “into” the devices. The algebraic sign corrects the direction if necessary.

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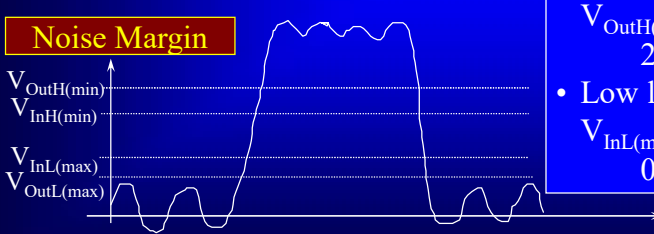
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Static Parameters of ICs

- $\{I_{OutH}, I_{OutL}\} \equiv$ output current if logic is $\{H,L\}$
- $\{I_{InH}, I_{InL}\} \equiv$ input current if logic is $\{H,L\}$
- $n_H = \{F.O.\}_H = |I_{OutH(max)} / I_{InH(max)}|$; $n_L = \{F.O.\}_L = |I_{OutL(max)} / I_{InL(max)}|$;
 $n = \{Fan\ Out\} = \min\{n_H, n_L\}$
- Ex: $15mA/1mA = 15 = n_H$, $10mA/2mA = 5 = n_L$, hence $n = 5$
- TTL is said to be “current sinking logic”
- n_L will likely be the limiting parameter

For LS-TTL

- High level noise margin $\equiv V_{OutH(min)} - V_{InH(min)} = 2.7V - 2.0V \approx 0.7V$
- Low level noise margin $\equiv V_{InL(max)} - V_{OutL(max)} = 0.8V - 0.5V \approx 0.3V$

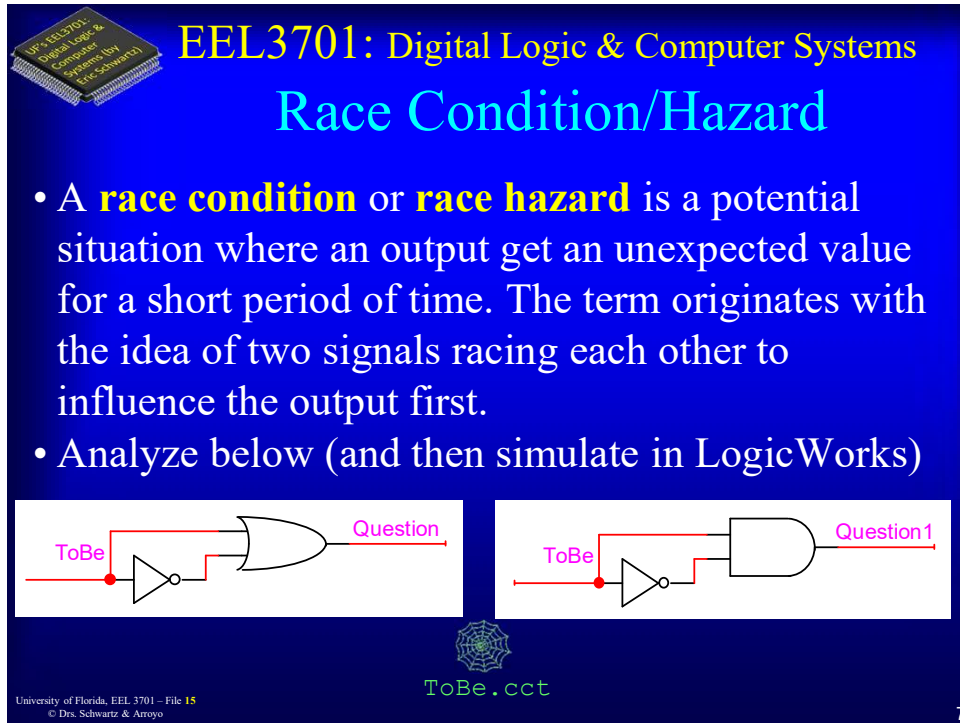


Noise Margin

$V_{OutH(min)}$
 $V_{InH(min)}$
 $V_{InL(max)}$
 $V_{OutL(max)}$

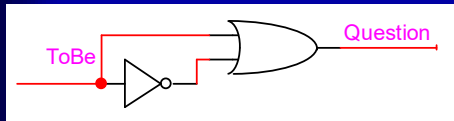
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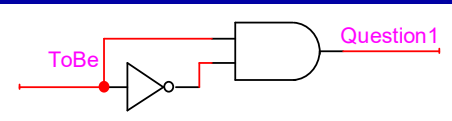


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Race Condition/Hazard

- A **race condition** or **race hazard** is a potential situation where an output get an unexpected value for a short period of time. The term originates with the idea of two signals racing each other to influence the output first.
- Analyze below (and then simulate in LogicWorks)



Question



Question1

ToBe.cct

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The End!

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